## **Electronic Supplementary Information (ESI)**

## Anisotropic two-dimensional sheets assembled from rod-shaped metal complexes

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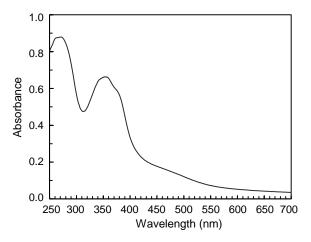
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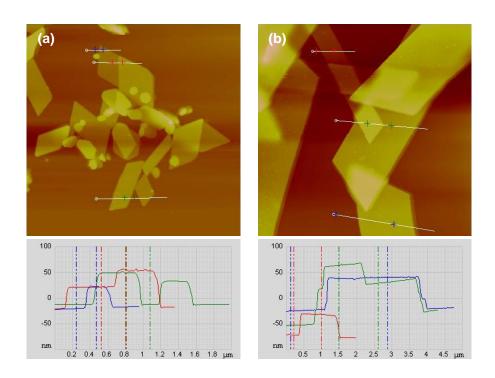
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## Instrumentation

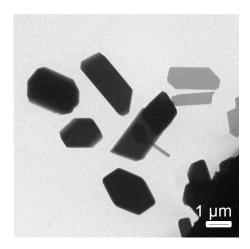
The TEM (transmission electron microscope) was performed at 100 kV using HITACHI H-7650. The sample was prepared by placing a drop of PdCl<sub>2</sub>Az<sub>2</sub> suspension onto a silicon oxide coated gold grid, and drying in a nitrogen atmosphere at room temperature. Optical microscopy (OM) and polarized optical microscopy (POM) images were obtained using an Olympus BX51 microscope, after putting a drop of suspension on a clean glass substrate. We employed topping mode atomic force microscopy (AFM: Veeco Instruments Inc., AFM probes: NCH silicon pointprobe® tip, NanoWorld, Switzerland) to characterize the topographic morphology of the samples on a mica substrate. Absorption spectra were obtained using a Shimadzu UV-3150 UV-VIS-NIR scanning spectrophotometer and a JASCO MSV-350 UV-vis microspectrophotometer. X-ray diffraction (XRD) patterns of planar sheets were measured in reflection mode with CuKα radiation on a Bruker D8 diffractometer.



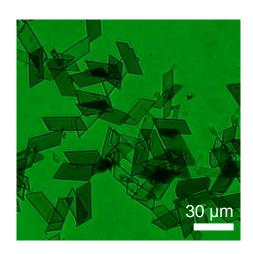
**Fig. S1** UV-vis absorption spectrum of suspensions in  $2 \times 10^{-5}$  M THF/H<sub>2</sub>O (1/4, v/v).



**Fig. S2** AFM images and height profiles of parallelogram-shaped sheets prepared from (a)  $2 \times 10^{-5}$  M THF/H<sub>2</sub>O (1/4, v/v) (6 × 6  $\mu$ m<sup>2</sup>) and (b)  $1 \times 10^{-4}$  M THF/H<sub>2</sub>O (1/1, v/v) (10 × 10  $\mu$ m<sup>2</sup>).



**Fig. S3** TEM image of  $8 \times 10^{-5}$  M DMF/H<sub>2</sub>O (5/1, v/v).



**Fig. S4** POM image of microsheets prepared from  $1.1 \times 10^{-3}$  M THF/H<sub>2</sub>O.

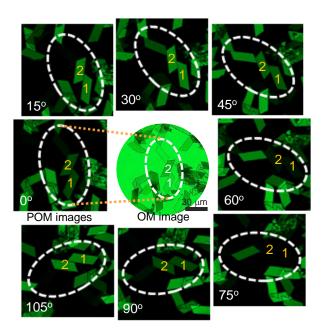
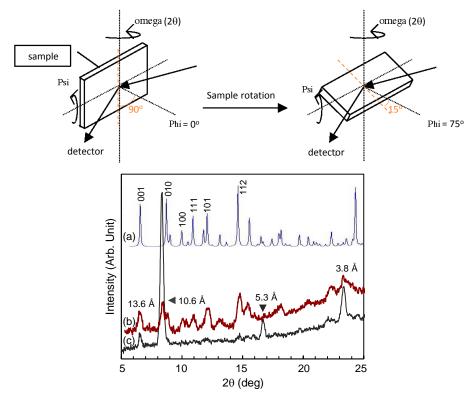
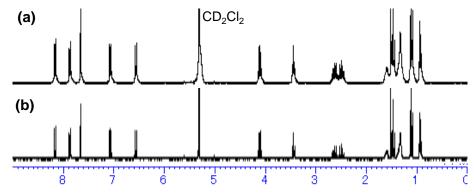


Fig. S5 POM and OM images of microsheets prepared from  $1.1 \times 10^{-3}$  M THF/H<sub>2</sub>O.



**Fig. S6** XRD patterns of (a) the simulated pattern of the single crystal, (b) taken at  $75^{\circ}$ , and (c) taken at  $0^{\circ}$ .



**Fig. S7** NMR spectra of  $PdCl_2Az_2$ . (a) purified palladium complex and (b) redissolved in  $CD_2Cl_2$  after the formation of complex sheets in  $5.3 \times 10^{-3}$  M THF/H<sub>2</sub>O (2/1, v/v).